CERAMIC DISC CAPACITORS CHARA CTERISTICS

項目 ITEM	規格 SPECIFICATION		檢測方法及條件 TEST METHOD AND CONDITION
10. 高溫負荷 (壽命試驗) Loading life High temperature Loading	外觀 Appearance	無顯著之異常. No marked defect.	≤500VDC 在試驗溫度下連續施加2倍W.V. (充放電電流50mA以下)1000(+48/-0)小時; ≥1KVDC 在試驗溫度下連續施加1.25倍W.V. (充放電電流50mA以下)1000(+48/-0)小時; ≤500VDC Apply 2 times rated voltage at maximum operating temperature for 1000(+48/-0)hours ≥1KVDC Apply 1.25 times rated voltage at maximum operating temperature for 1000(+48/-0)hours Test temp.: T.C.、Y5E、Y5P、Y5U、Z5U、X5R Y5V、Z5V: 85℃±5℃ NPO N750、X7R : 125℃±5℃ Change or discharge current shall not exceed 50mA.. 試驗后：取出於室溫中，T.C.類需放置24小時以上方可測定；HIK、半導體類需放置48小時以上方可測定. Capacitor shall be measured after leaving at room temperature T.C.:24Hr HIK、S.C.:48Hr
	靜電容量 變化率 Capacitance change	T.C.: ±7.5% or ±0.75PF; HIK、半導體類(S.C.): Y5E、Y5P: ±15%; X7R、X5R: ±20%; Z5U、Y5U: ±25%; Z5V、Y5V: ±30%。	
	Q or DF	T.C. C<30PF: Q≥200+10×C C≥30PF: Q≥500 HIK: Y5E、Y5P、X7R、 X5R、Z5U、Y5U Df≤5% Z5V、Y5V DF≤7.5% 半導體(S.C.): Y5P、Y5U DF≤7.5% Y5V Df≤10%	
	絕緣電阻 Insulation resistance	T.C.:1000MΩ min HIK:500MΩ min S.C.:25MΩ×UF min	
11. 端子強度 Strength of lead	抗拉強度 Pull	導線不斷裂，電容器本體不破損. Lead wire shall not cut off and capacitor shall not be broken.	垂直固定被測物本體，引線向下，負荷施力方向爲導線引出方向，施加負荷爲1.0kg,時間爲5秒 As a figure fix the body of capacitor, apply a tensile weight gradually to each lead in the radial direction of capacitor up to 1.0kg, and keep it for 5 secretary..
	彎曲強度 Bending		固定被測物，施加0.5kg於端子引線間並彎曲90°，回復原來之位置，並反向彎曲90°，1次彎曲時間爲5秒. Each lead wire shall be subjected to 0.5kg weight and then a 90° bend, at the point of egress, in one direction, return to original position and then a 90° bend in the opposite direction at the rate of one bend in 5 secretary..